

Search Notes

Application/Control No.

10/614,217

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

CHA, ELLIS T.

Art Unit

2652

SEARCHED

Class	Subclass	Date	Examiner
Updated			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR